

IRIS TR lines with wings: non-Maxwellian analysis

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Contributed Talk

1. Fundamental physical processes and modeling

Transition-Region lines with strong wings: Non-Maxwellian analysis of line profiles and intensities

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We analyze the IRIS observation of an active region containing bright transition-region (TR) loops. Locations showing symmetric profiles of the Si IV and O IV lines are selected. In nearly all of these locations, the Si IV line at 1402.8 Å is much stronger than the neighboring O IV lines. Furthermore, all TR lines show strong (S/N > 10) and extended wings, i.e., a non-Gaussian profile. We found that the non-Maxwellian κ -distributions approximate these profiles better or at least equally well as double-Gaussian fits. The values of κ found are typically very low, in the range of 1.7 - 2.5. Similar κ values are obtained from fitting the intensities of the O IV lines relative to Si IV. Furthermore, all TR lines have the same κ and width, irrespective of whether the line is an allowed or intercombination transition. However, we also found a single location showing very strong but Gaussian Si IV line, indicating that instrumental effects can be ruled out.



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Synthetic IRIS TR spectrum



Dudík et al. (2014), ApJ 780, L12

- Predicted IRIS FUV2 spectrum for a typical quiet Sun DEM:
 O IV 1401.2 Å line stronger than the Si IV 1402.8 Å
- For AR, with steeper DEM slope, O IV > Si IV also

TR Lines: Challenges



TR Lines: Challenges



OIV > SiIV ?: Single Solar Case



Non-Gaussian Line Profiles



counts per pixel in 115 s

α Centauri A+B



Ayres (2015), Astron. J., 149, 58

Non-Gaussian Line Profiles: *IRIS*



The *k*-distributions



*k***-Distributions:** Line Profiles



*k***-distributions:** Line intensities



Dzifčáková & Dudík (2013), ApJS, 206, 6 Dudík et al. (2014), ApJL, 780, L12 Dzifčáková et al. (2017), A&A, 603, A14

- For TR lines, ion abundance peaks are shifted to lower T
- High-energy tail: ionization rate enhanced by orders of magnitude
- Recombination enhanced by a factor of < 2</p>

IRIS Example Spectrum



IRIS Example Spectrum: Fitting



IRIS Example Spectrum: Fitting



IRIS Example Spectrum: Fitting

Line	$\lambda_0 \; [{ m \AA}]$	I_0 [DN]	w_{κ} [Å]	κ	FWHM_{κ} [Å]	$T_{\rm i}$ [MK]
O IV 1399.78 Å	1399.831 ± 0.001	385 ± 6	0.143 ± 0.010	2.16 ± 0.17	0.20 ± 0.08	1.81 ± 0.26
O IV 1401.16 Å	1401.218 ± 0.000	1399 ± 10	0.127 ± 0.003	2.35 ± 0.08	0.20 ± 0.05	1.43 ± 0.06
Si IV 1402.77 Å	1402.820 ± 0.000	4598 ± 18	0.136 ± 0.001	2.16 ± 0.03	0.19 ± 0.02	2.86 ± 0.06
O IV 1404.82 Å (bl S IV)	1404.855 ± 0.001	383 ± 6	0.163 ± 0.018	1.90 ± 0.13	0.19 ± 0.13	2.35 ± 0.52
S IV 1406.06 Å	1406.103 ± 0.001	282 ± 5	0.144 ± 0.021	1.91 ± 0.18	0.17 ± 0.17	3.64 ± 1.08

- (Almost) consistent κ values derived from all five TR lines
- All five lines have the same FWHM
- Significant non-thermal widths

$$w_{\kappa}^{2} = \frac{1}{2} \frac{\lambda_{0}^{2}}{c^{2}} (\theta^{2} + (\theta^{(\mathrm{nth})})^{2}) = (w_{\kappa}^{(\mathrm{th})})^{2} + (w_{\kappa}^{(\mathrm{nth})})^{2}$$

Line	w_{κ} [Å]	$\log(T_{\max, Maxw} [K])$	$w_{ m Maxw}^{ m (th)}$	$w_{ m Maxw}^{ m (nth)}$	$\log(T_{\max,\kappa=2} [K])$	$w_{\kappa=2}^{(\mathrm{th})}$	$w_{\kappa=2}^{(\mathrm{nth})}$
O IV 1399.78 Å	0.143 ± 0.010	5.15	0.040	0.137	4.45	0.018	0.141
O IV 1401.16 Å	0.127 ± 0.003	5.15	0.040	0.121	4.45	0.018	0.126
Si IV 1402.77 Å	0.136 ± 0.001	4.90	0.023	0.134	4.10	0.009	0.136
O IV 1404.82 Å (bl S IV)	0.163 ± 0.018	5.15	0.040	0.158	4.45	0.018	0.162
S IV 1406.06 Å	0.144 ± 0.021	5.05	0.025	0.141	4.20	0.009	0.143
Si IV 1402.77 A O IV 1404.82 Å (bl S IV) S IV 1406.06 Å	0.136 ± 0.001 0.163 ± 0.018 0.144 ± 0.021	$4.90 \\ 5.15 \\ 5.05$	0.023 0.040 0.025	$0.134 \\ 0.158 \\ 0.141$	4.10 4.45 4.20	0.009 0.018 0.009	0.13 0.16 0.14





More cases...



Si IV: Case of a Gaussian Profile



- Detection of a single, very bright Gaussian pixel
- Third brightest pixel with symmetric profiles
- The non- Gaussian profiles are not caused by instrumental effects
- Larger / asymmetric residuals: Possibly 2 Gaussian components

Interpretation

Residuals



- Similar profiles seen in the X8.3-flare of 2017 Sept 10
- EIS Fe XXIV with $\kappa \approx 2$
- only in RHESSI and EOVSA sources
- Ion acceleration ($T > 10^8 K$)
- Turbulence (v_{nth} > 200 km/s)



Polito, Dudík, et al. (2018), to be submitted to ApJ

Tails too strong? : κ + NEI



Summary

- Detected non-Gaussian, highly symmetric profiles of TR lines in 120 pixels
- Typical κ values found from profiles are κ ≈ 1.7 – 2.5
- This is not an instrumental effect
 we detected a Gaussian pixel
- Typical κ values found from fitting of relative intensities are κ ≈ 2 3 (but sensitive to abundances)
- The Si IV 1402.8 Å line is optically thin



Dudík et al. (2017), ApJ, 842, 19

Review on non-Maxwellians and non-equilibrium ionization: Dudík et al. (2017), Solar Phys., 292, 100

Is the SI IV optically thick?

The optical thickness is given by (e.g., Buchlin & Vial 2009, A&A, 503, 559):

$$\tau(\lambda) = \tau_0(\lambda_0) \Phi(\lambda) = \frac{\lambda_0^4 A_{ij} \Phi(\lambda)}{4\pi^{3/2} c \Delta \lambda_{\rm D}} \frac{N({\rm Si}^{+3})}{N({\rm Si})} A({\rm Si}) \frac{N_{\rm H}}{N_{\rm e}} \langle N_{\rm e} \rangle \Delta s$$

For Maxwellian and thermal width, we get

$$\tau_0 \approx 0.26 f \frac{\langle N_{\rm e} \rangle}{10^{10} \,\mathrm{cm}^{-3}}$$

- For κ = 2, the numerical factor is about 1.5 (due to lower thermal width and higher N(Si⁺³) / N(Si)
- For the *observed* width and a Maxwellian, we get

$$\tau_0 \approx 0.02 f \frac{\langle N_{\rm e} \rangle}{10^{10} \,\mathrm{cm}^{-3}}$$

For κ = 2, the numerical factor is about 0.06

Is the SI IV optically thick?

• If the line is optically thick, then the profile should be (for *S* = const.) $I^*(\lambda) = \int_{0}^{\tau(\lambda)} S_{\lambda} \exp(-t_{\lambda}) dt_{\lambda} = S_{\lambda} \left[1 - \exp(-\tau(\lambda))\right]$



Multi-Component Si IV?

The FWHM changes as

FWHM_{$$\kappa$$}^{*}(τ_0)² = 8($\kappa - 3/2$) $w_{\kappa}^2 \left[\left(\frac{\tau_0}{\ln(2) - \ln(\exp(-\tau_0) + 1)} \right)^{\frac{1}{\kappa}} - 1 \right]$

- Recall that the FWHM of the Si IV line is the same as for the O IV and S IV
- For solar conditions,
 O IV lines are always optically thin because of their small A_{ii}
- ⇒ the Si IV is optically *thin*

